

1765
RECEIVED
MAR 03 2003
GROUP 1700

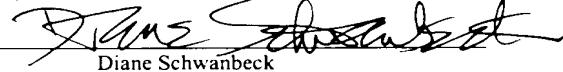
PATENT

In the United States Patent and Trademark Office

Applicants: Linda BRALY et al.)
Applicants' Reference: LAM2P298)
Application No. 10/002,676)
Filed: October 31, 2001)
Title: METHOD FOR PLANARIZATION ETCH)
WITH IN-SITU MONITORING BY)
INTERFEROMETRY PRIOR TO RECESS ETCH)

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, DC 20231 on February 20, 2003.

Signed: 
Diane Schwanbeck

Separate Letter to the Official Draftsperson

Commissioner for Patents
Box: Official Draftsperson
Washington, D.C. 20231

Dear Sir:

Applicants hereby attach thirteen (13) sheets of formal drawings (Figures 1-13) for the above-referenced patent application. In the event the Draftsperson has any questions concerning the formal drawings, he or she is respectfully requested to contact the undersigned. If any fees are due in connection with the filing of these drawings, then please charge such fees to our Deposit Account No. 50-0805 (Order No. LAM2P298).

Respectfully submitted,
MARTINE & PENILLA, LLP


Edmund H. Mizumoto, Esq.
Reg. No. 46,938

710 Lakeway Drive, Suite 170
Sunnyvale, California 94085
(408) 749-6900
Customer No. 25920